

PATENT

Atty. Docket No. MICRON-01023

ABSTRACT

1 An on-chip circuit for defect testing with the ability to maintain a substrate voltage at
2 a level more positive or more negative than a normal negative operating voltage level of the
3 substrate. This is accomplished with a chain of MOSFETs that are configured to operate as a
4 chain of resistive elements or diodes wherein each element in the chain may drop a portion of
5 a supply voltage coupled to a first end the chain. The substrate is coupled to a second end of
6 the chain. The substrate voltage level is essentially equivalent to the supply voltage level less
7 the voltage drops across the elements in the diode chain. A charge pump maintains the
8 substrate voltage level set by the chain. Performing chip testing with the substrate voltage
9 level more negative than the normal negative voltage level facilitates detection of devices that
10 will tend to fail only at cold temperatures. Performing chip testing with the substrate voltage
11 level more positive than the normal negative voltage level facilitates detection of other margin
12 failures and ion contamination.

"Express Mail" mailing label number: EL709306914US

Date of Deposit: August 22, 2001

This paper or fee is being deposited on the date indicated above with the United States Postal Service pursuant to 37 CFR 1.10, and is addressed to the Commissioner for Patents, Box Patent Application, Washington, D.C. 20231.